

US00D500693S

(12) **United States Design Patent**
Graef et al.

(10) **Patent No.:** **US D500,693 S**
(45) **Date of Patent:** **** Jan. 11, 2005**

(54) **MEASUREMENT INSTRUMENT**

FOREIGN PATENT DOCUMENTS

(75) **Inventors:** **David Graef**, Campbell Hall, NY (US);
Phil Stearns, Colorado Springs, CO
(US); **Norio Shimomura**, Tokyo (JP);
Satoshi Hayasaka, Tokyo (JP)

JP	1178204	5/2003
JP	1178205	5/2003
JP	1178206	5/2003
JP	1178213	5/2003
JP	1178214	5/2003
JP	1178215	5/2003
JP	1178216	5/2003

(73) **Assignee:** **LeCroy Corporation**, Chestnut Ridge,
NY (US)

* cited by examiner

(**) **Term:** **14 Years**

Primary Examiner—Antoine D. Davis

(21) **Appl. No.:** **29/191,575**

(74) *Attorney, Agent, or Firm*—Frommer Lawrence &
Haug LLP; William S. Frommer

(22) **Filed:** **Oct. 9, 2003**

(57) **CLAIM**

(51) **LOC (7) Cl.** **10-04**

The ornamental design for the “measurement instrument,”
as shown.

(52) **U.S. Cl.** **D10/76**

(58) **Field of Search** D10/76; 702/189,
702/65, 125, 66–68; 324/555; 345/440,
175, 173, 440.1

DESCRIPTION

(56) **References Cited**

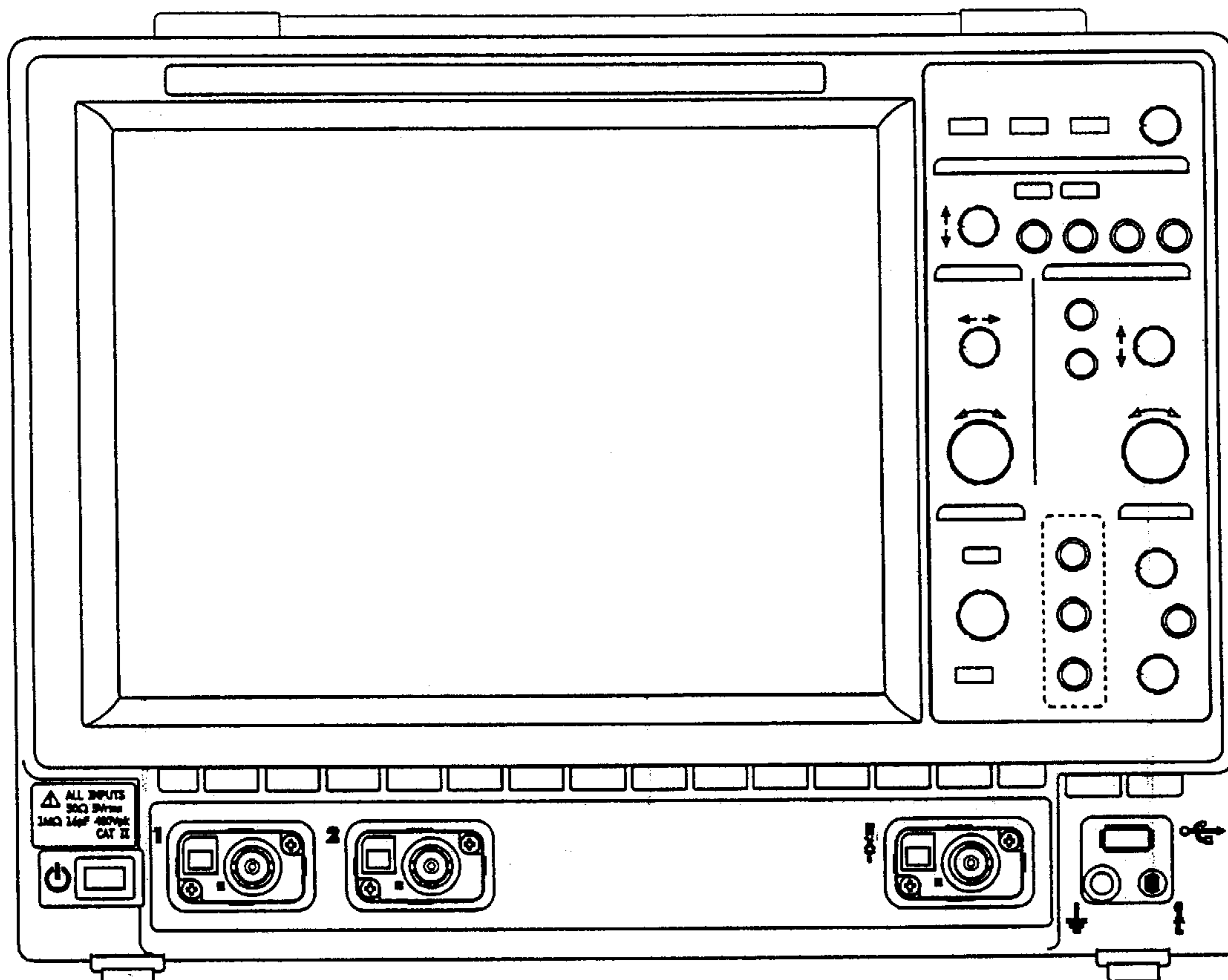
U.S. PATENT DOCUMENTS

6,515,484	B1	*	2/2003	Bald et al.	324/551
6,720,776	B2	*	4/2004	Anderson et al.	324/555
2001/0001850	A1	*	5/2001	Miller	702/67
2003/0191591	A1	*	10/2003	Iiyoshi et al.	702/68
2003/0204342	A1	*	10/2003	Law et al.	702/65

FIG. 1 is a front elevational view of a first embodiment of
the measurement instrument showing our new design;
FIG. 2 is a top plan view thereof;
FIG. 3 is a left side elevational view thereof;
FIG. 4 is a right side elevational view thereof;
FIG. 5 is a rear elevational view thereof; and,
FIG. 6 is a bottom plan view thereof.

The broken line showing is for illustrative purposes only and
forms no part of the claimed design.

1 Claim, 6 Drawing Sheets



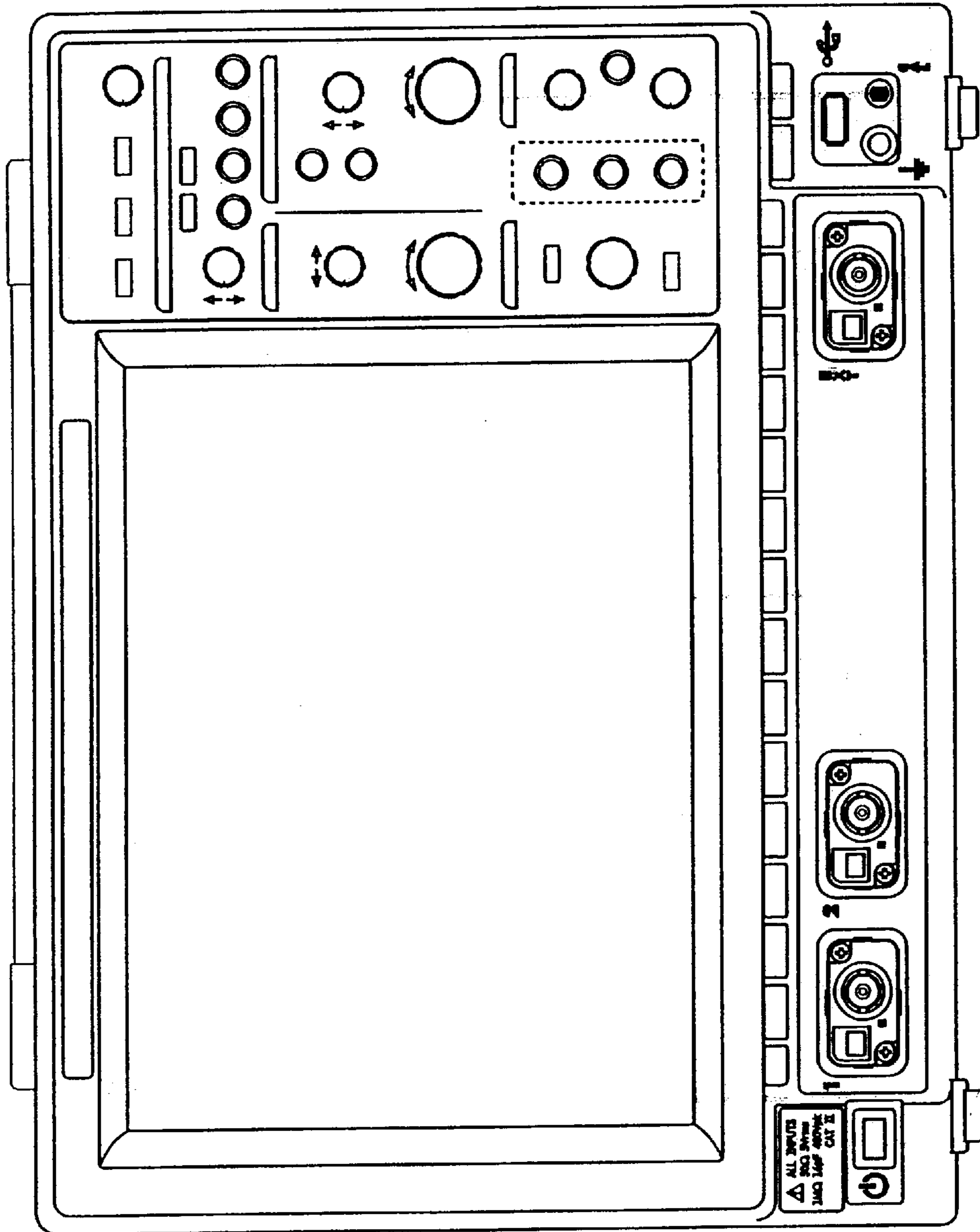


FIG. 1

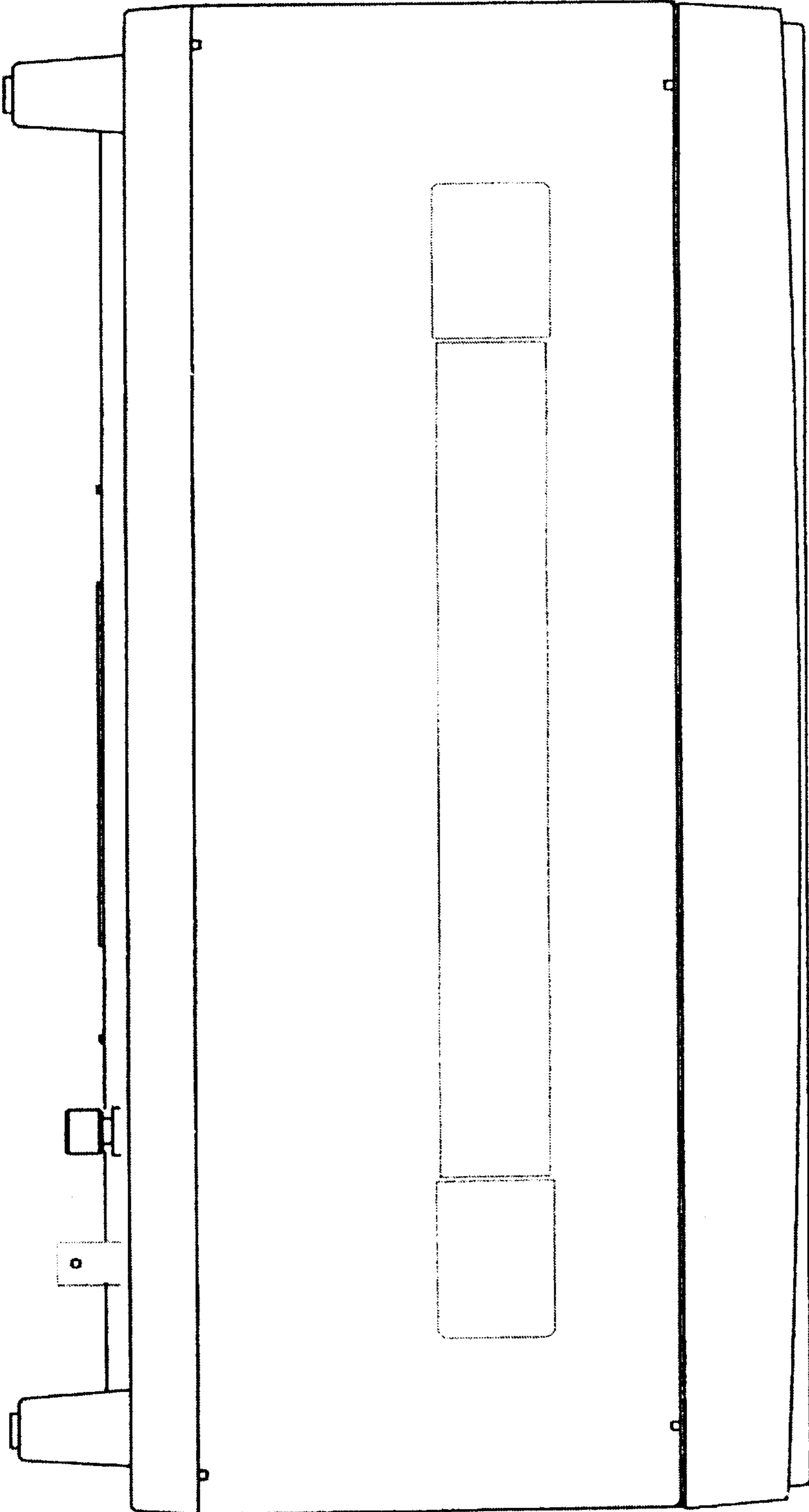


FIG. 2

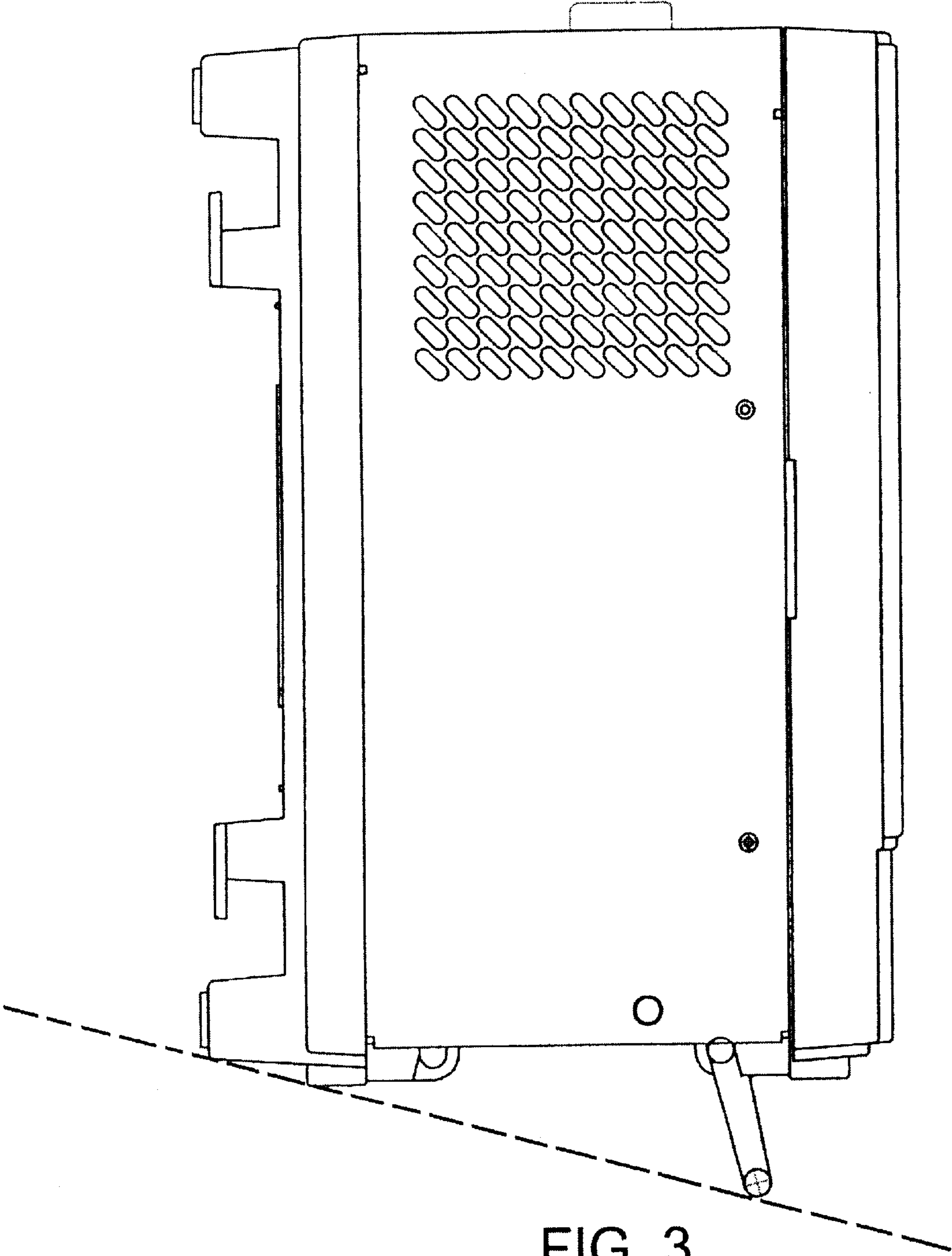


FIG. 3

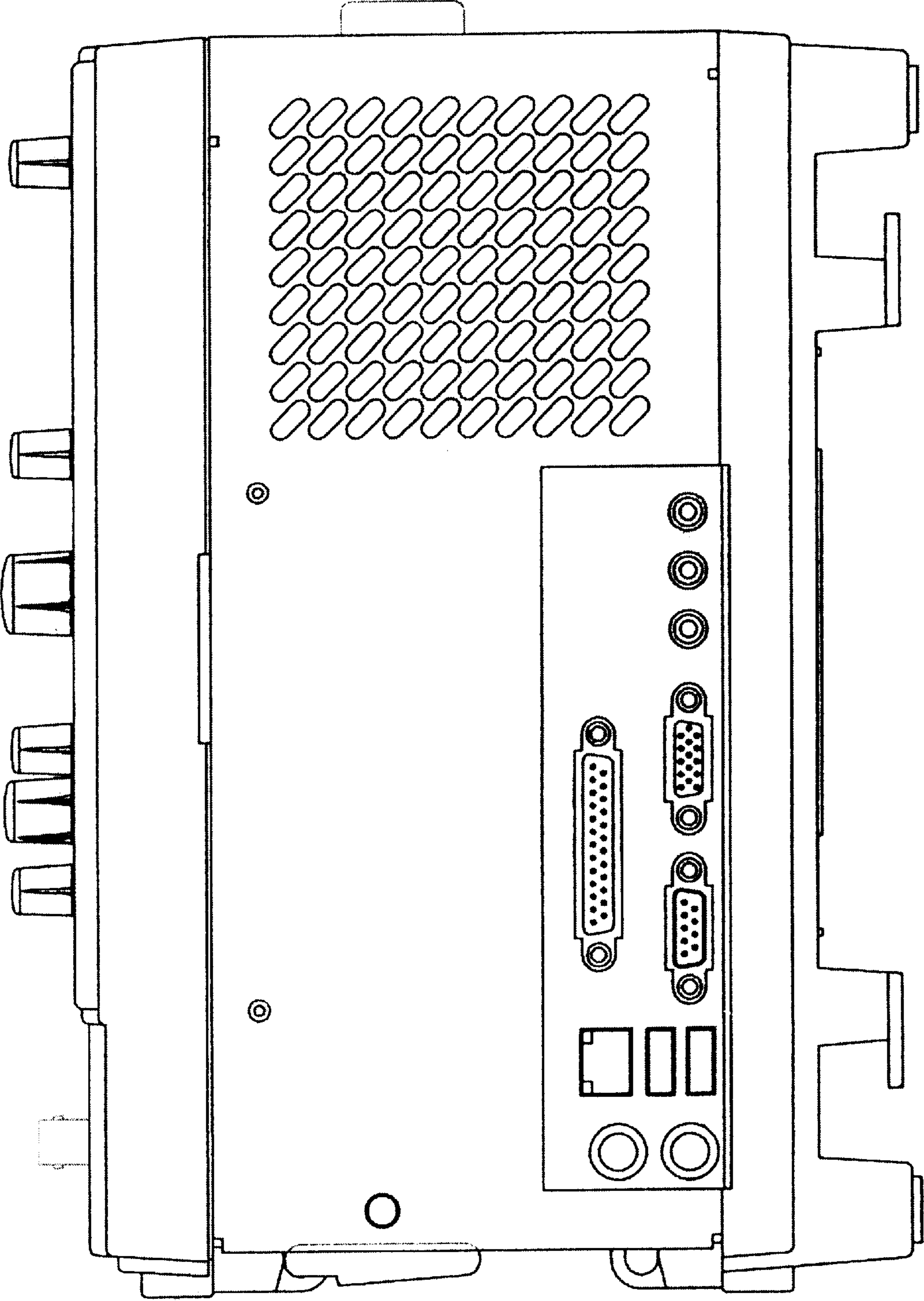


FIG. 4

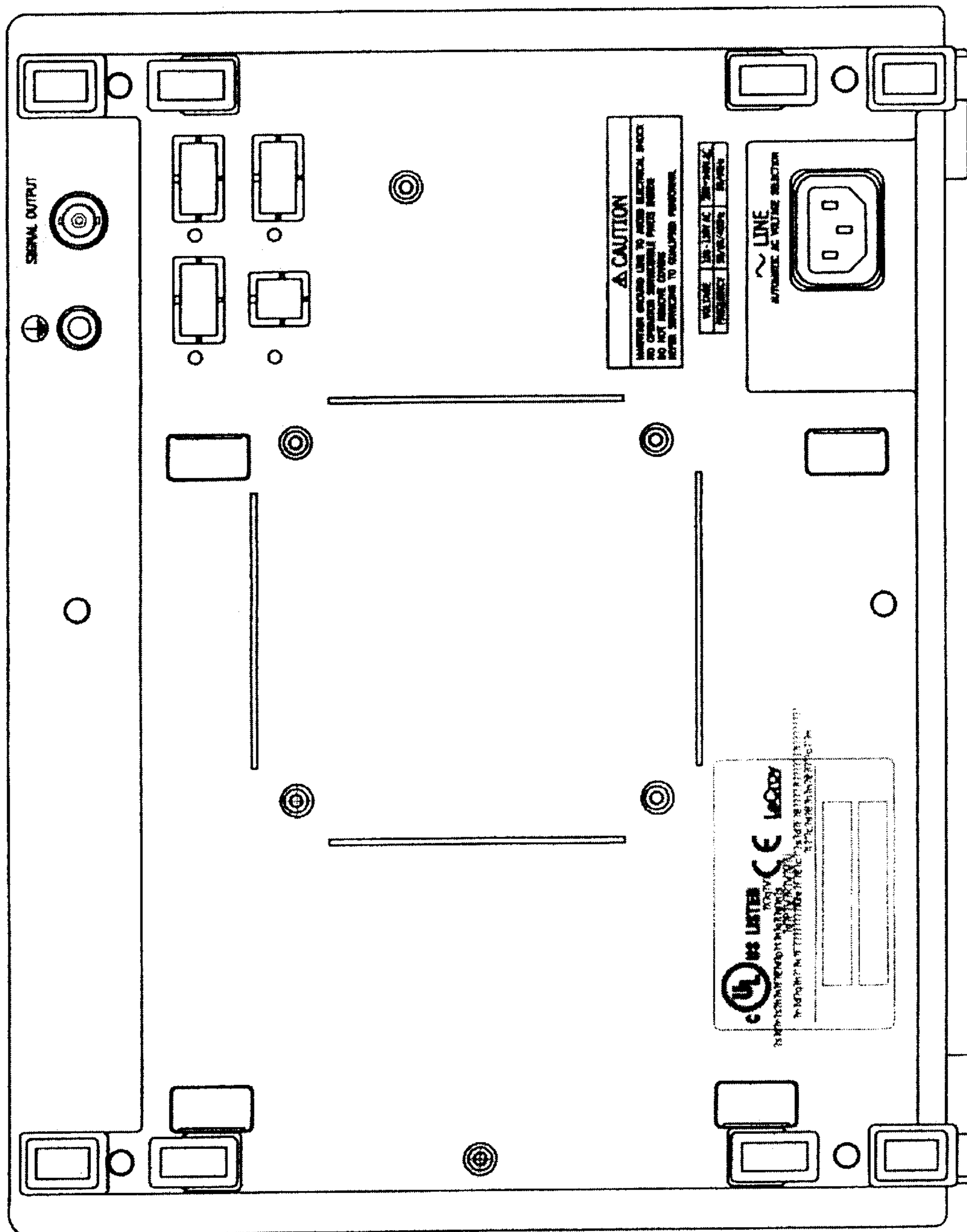


FIG. 5

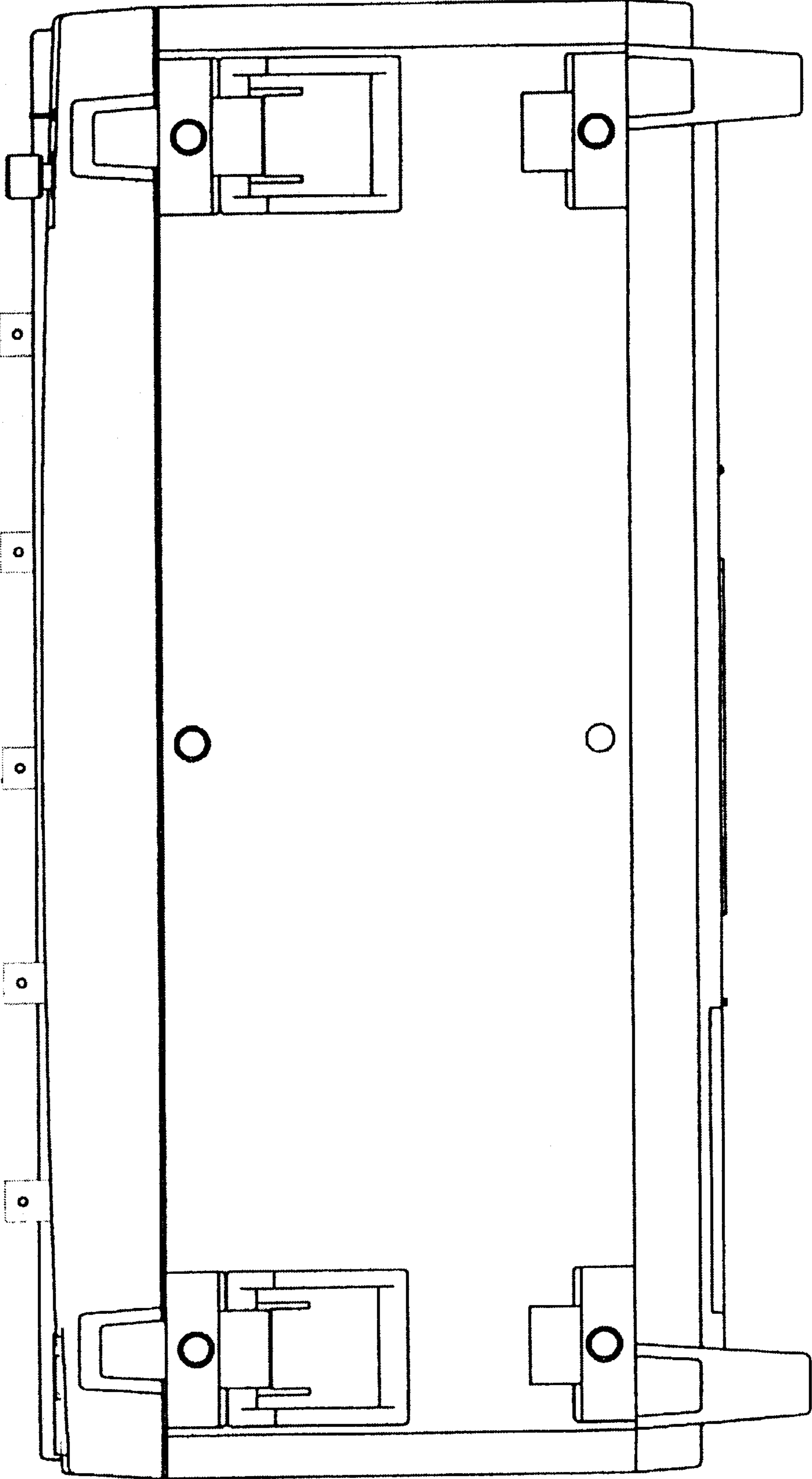


FIG. 6